

Notice of References Cited	Application/Control No. 10/623,767	Applicant(s)/Patent Under Reexamination YOSHINO ET AL.	
	Examiner Wayne Cai	Art Unit 2617	Page 1 of 1

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*	B	US-2003/0212745	11-2003	Caughey, David A.	709/206
*	C	US-6,473,629	10-2002	Chang, Yun-Seok	455/566
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NON-PATENT DOCUMENTS

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